

Notice of References Cited	Application/Control No. 09/886,598	Applicant(s)/Patent Under Reexamination HUA, PAUL	
	Examiner John M. Villecco	Art Unit 2612	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,872,470	02-1999	Mallinson et al.	327/94
	B	US-6,421,085	07-2002	Xu, Weize	348/308
	C	US-6,025,875	02-2000	Vu et al.	348/241
	D	US-6,697,108	02-2004	Chen et al.	348/241
	E	US-6,320,616	11-2001	Sauer, Donald Jon	348/241
	F	US-6,744,394	06-2004	Liu et al.	341/155
	G	US-6,784,824	08-2004	Quinn, Patrick J.	341/172
	H	US-6,441,852	08-2002	Levine et al.	348/308
	I	US-6,433,632	08-2002	Nakamura et al.	327/124
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 98/24092	06-1998	International P	Mallinson	G11C 27/02
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Yonemoto et al.; "A Numerical Analysis of a CMOS Image Sensor with a Simple Fixed-Pattern-Noise-Reduction Technology"; May 2002; IEEE Transactions on Electron Devices; Vol. 49, No. 5; 746-753
	V	Huang et al.; "Reduced Nonlinear Distortion in Circuits with Correlated Double Sampling"; 1996; IEEE
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.